

SN54LS299, SN74LS299, SN54S299, SN74S299 8-BIT UNIVERSAL SHIFT/STORAGE REGISTERS

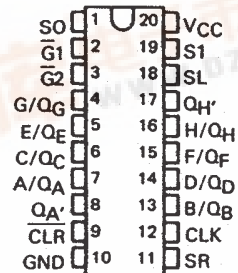
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- **Multiplexed Inputs/Outputs Provide Improved Bit Density**
- **Four Modes of Operations:**

Hold (Store)	Shift Left
Shift Right	Load Data
- **Operates with Outputs Enabled or at High Z**
- **3-State Outputs Drive Bus Lines Directly**
- **Can Be Cascaded for N-Bit Word Lengths**
- **SN54LS323 and SN74LS323 Are Similar But Have Synchronous Clear**
- **Applications:**
 Stacked or Push-Down Registers
 Buffer Storage, and Accumulator Registers

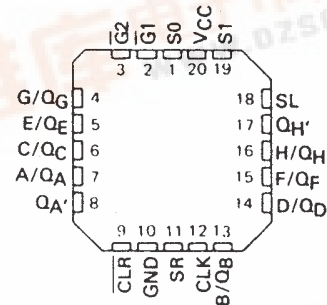
SN54LS299, SN54S299 . . . J OR W PACKAGE
 SN74LS299, SN74S299 . . . DW OR N PACKAGE

(TOP VIEW)



SN54LS299, SN54S299 . . . FK PACKAGE

(TOP VIEW)



TYPE	GUARANTEED	TYPICAL
	SHIFT (CLOCK)	POWER
	FREQUENCY	DISSIPATION
'LS299	25 MHz	175 mW
'S299	50 MHz	700 mW

description

These Schottky TTL eight-bit universal registers feature multiplexed inputs/outputs to achieve full eight-bit data handling in a single 20-pin package. Two function-select inputs and two output-control inputs can be used to choose the modes of operation listed in the function table.

Synchronous parallel loading is accomplished by taking both function-select lines, S0 and S1, high. This places the three-state outputs in a high-impedance state, which permits data that is applied on the input/output lines to be clocked into the register. Reading out of the register can be accomplished while the outputs are enabled in any mode. A direct overriding input is provided to clear the register whether the outputs are enabled or off.

FUNCTION TABLE

MODE	INPUTS						INPUTS/OUTPUTS								OUTPUTS			
	CLR	FUNCTION SELECT		OUTPUT CONTROL		CLK	SERIAL		A/QA	B/QB	C/QC	D/QD	E/QE	F/QF	G/QG	H/QH	QA'	QH'
		S1	S0	G1†	G2†		SL	SR										
Clear	L	X	L	L	L	X	X	X	L	L	L	L	L	L	L	L	L	L
	L	L	X	L	L	X	X	X	L	L	L	L	L	L	L	L	L	L
	L	H	H	X	X	X	X	X	X	X	X	X	X	X	X	X	X	X
Hold	H	L	L	L	L	X	X	X	QA0	QB0	QC0	QD0	QE0	QF0	QG0	QH0	QA0	QH0
	H	X	X	L	L	L	X	X	QA0	QB0	QC0	QD0	QE0	QF0	QG0	QH0	QA0	QH0
Shift Right	H	L	H	L	L	†	X	H	H	QAn	QBn	QCn	QDn	QEn	QFn	QGn	H	QGn
	H	L	H	L	L	†	X	L	L	QAn	QBn	QCn	QDn	QEn	QFn	QGn	L	QGn
Shift Left	H	H	L	L	L	†	H	X	QBn	QCn	QDn	QEn	QFn	QGn	QHn	H	QBn	H
	H	H	L	L	L	†	L	X	QBn	QCn	QDn	QEn	QFn	QGn	QHn	L	QBn	L
Load	H	H	H	X	X	†	X	X	a	b	c	d	e	f	g	h	a	h

† When one or both output controls are high the eight input/output terminals are disabled to the high-impedance state; however, sequential operation or clearing of the register is not affected.

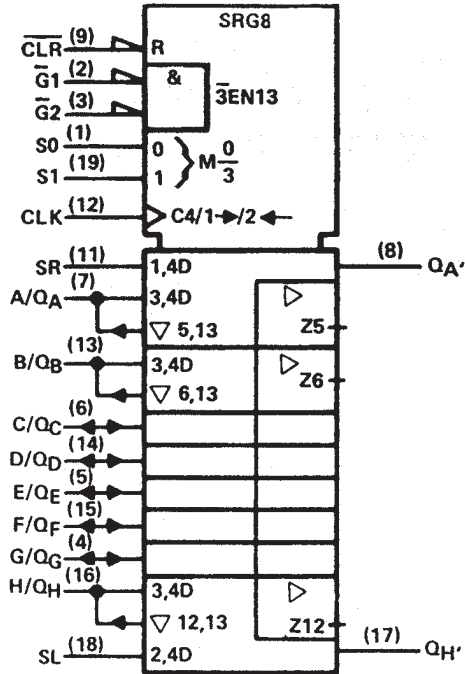
a . . . h = the level of the steady-state input at inputs A through H, respectively. These data are loaded into the flip-flops while the flip-flop outputs are isolated from the input/output terminals.



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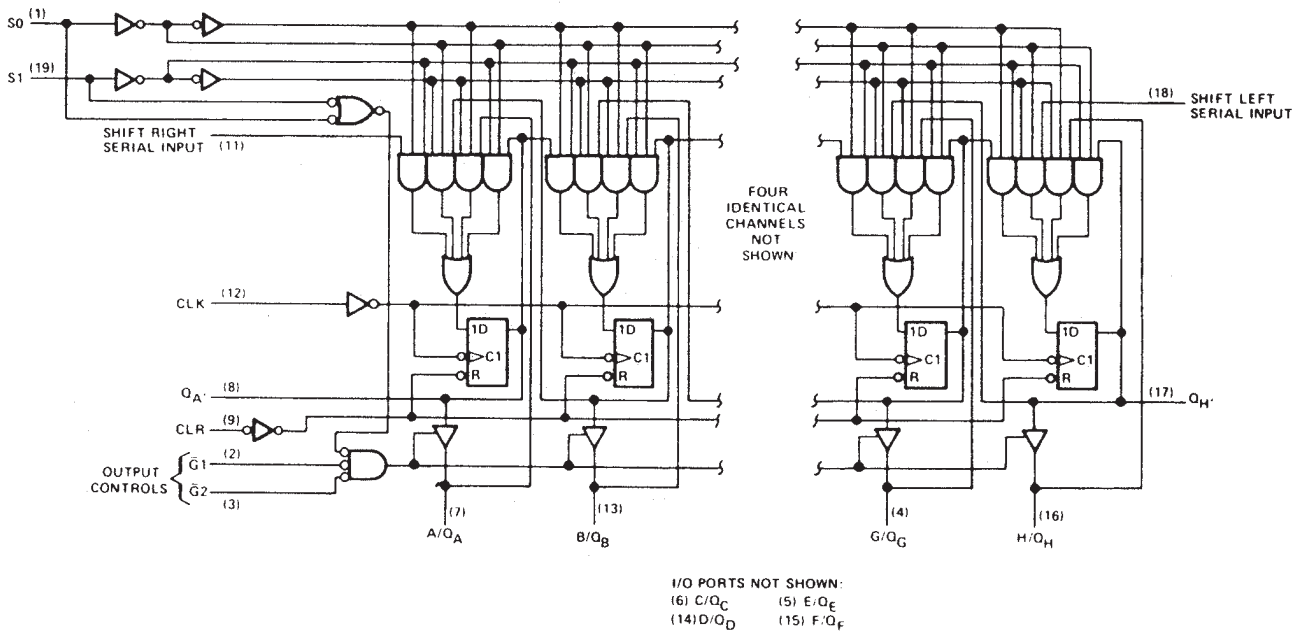
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logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for DW, J, N, and W packages.

logic diagram (positive logic)

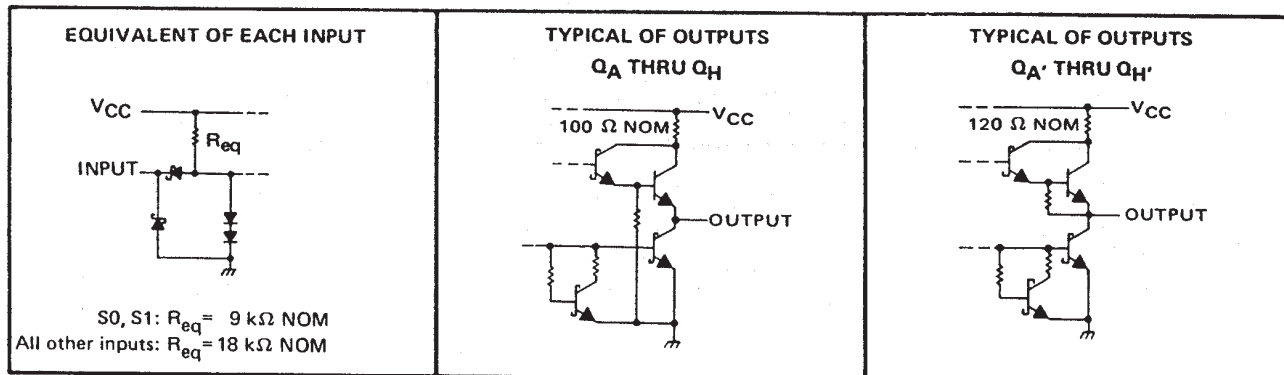


Pin numbers shown are for DW, J, N, and W packages.

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schematics of inputs and outputs



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} (see Note 1)	7 V
Input voltage	7 V
Off-state output voltage	5.5 V
Operating free-air temperature range: SN54LS299	-55°C to 125°C
SN74LS299	0°C to 70°C
Storage temperature	-65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

recommended operating conditions

		SN54LS299			SN74LS299			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, V_{CC}		4.5	5	5.5	4.75	5	5.25	V
High-level output current, I_{OH}	Q_A thru Q_H			-1			-2.6	mA
	Q_A' or Q_H'			-0.4			-0.4	
Low-level output current, I_{OL}	Q_A thru Q_H			12			24	mA
	Q_A' or Q_H'			4			8	
Clock frequency, f_{clock}		0		20	0		20	MHz
Width of clock pulse, $t_w(\text{clock})$	Clock high	30			30			ns
	Clock low	18			10			
Width of clear pulse, $t_w(\text{clear})$	Clear low	25			20			ns
Setup time, t_{su}	Select	35 [†]			35 [†]			ns
	High-level data [†]	20 [†]			20 [†]			
	Low-level data [†]	20 [†]			20 [†]			
	Clear inactive-state	24 [†]			20 [†]			
Hold time, t_h	Select	10 [†]			10 [†]			ns
	Data [†]	3 [†]			0 [†]			
Operating free-air temperature, T_A		-55		125	0		70	$^{\circ}\text{C}$

[†] Data includes the two serial inputs and the eight input/output data lines.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS†	SN54LS299		SN74LS299		UNIT		
			MIN	TYP‡	MAX	MIN		TYP‡	MAX
V _{IH}	High-level input voltage		2		2		V		
V _{IL}	Low-level input voltage		0.7		0.8		V		
V _{IK}	Input clamp voltage	V _{CC} = MIN, I _I = -18 mA	-1.5		-1.5		V		
V _{OH}	High-level output voltage	Q _A thru Q _H	2.4 3.2		2.4 3.1		V		
		Q _{A'} or Q _{H'}	2.5 3.4		2.7 3.4				
V _{OL}	Low-level output voltage	Q _A thru Q _H	V _{CC} = MIN, I _{OL} = 12 mA	0.25 0.4		0.25 0.4		V	
			V _{CC} = MIN, I _{OL} = 24 mA			0.35 0.5			
		Q _{A'} or Q _{H'}	V _{CC} = MIN, I _{OL} = 4 mA	0.25 0.4		0.25 0.4			
			V _{CC} = MIN, I _{OL} = 8 mA			0.35 0.5			
I _{OZH}	Off-state output current, high-level voltage applied	Q _A thru Q _H	V _{CC} = MAX, V _O = 2.7 V		40		μA		
I _{OZL}	Off-state output current, low-level voltage applied	Q _A thru Q _H	V _{CC} = MAX, V _O = 0.4 V		-400		μA		
I _I	Input current at maximum input voltage	S0, S1	V _{CC} = MAX	V _I = 7 V	200		200	μA	
		A thru H		V _I = 5.5 V	100		100		
		Any other		V _I = 7 V	100		100		
I _{IH}	High-level input current	A thru H, S0, S1	V _{CC} = MAX, V _I = 2.7 V	40		40		μA	
		Any other		20		20			
I _{IL}	Low-level input current	S0, S1	V _{CC} = MAX, V _I = 0.4 V	-0.8		-0.8		mA	
		Any other		-0.4		-0.4			
I _{OS}	Short-circuit output current §	Q _A thru Q _H	V _{CC} = MAX	-30 -130		-30 -130		mA	
		Q _{A'} or Q _{H'}		-20 -100		-20 -100			
I _{CC}	Supply current		V _{CC} = MAX		33 53		33 53		mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡ All typical values are at V_{CC} = 5 V, T_A = 25°C.

§ Not more than one output should be shorted at a time and duration of the short-circuit should not exceed one second.

switching characteristics, V_{CC} = 5 V, T_A = 25°C

PARAMETER¶	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
f _{max}			See Note 2	20	35		MHz
t _{PLH}	CLK	Q _{A'} or Q _{H'}	R _L = 2 kΩ, C _L = 15 pF	22 33		ns	
t _{PHL}				26 39			
t _{PHL}	$\overline{\text{CLR}}$	Q _{A'} or Q _{H'}		27 40		ns	
t _{PLH}	CLK	Q _A thru Q _H	R _L = 665 Ω, C _L = 45 pF	17 25		ns	
t _{PHL}				26 39			
t _{PHL}	$\overline{\text{CLR}}$	Q _A thru Q _H		26 40		ns	
t _{PZH}	$\overline{\text{G}}1, \overline{\text{G}}2$	Q _A thru Q _H		13 21		ns	
t _{PZL}				19 30			
t _{PHZ}	$\overline{\text{G}}1, \overline{\text{G}}2$	Q _A thru Q _H	R _L = 665 Ω, C _L = 5 pF	10 20		ns	
t _{PLZ}				10 15			

¶ f_{max} ≡ maximum clock frequency

t_{PLH} ≡ propagation delay time, low-to-high-level output.

t_{PHL} ≡ propagation delay time, high-to-low-level output

t_{PZH} ≡ output enable time to high level

t_{PZL} ≡ output enable time to low level

t_{PHZ} ≡ output disable time from high level

t_{PLZ} ≡ output disable time from low level

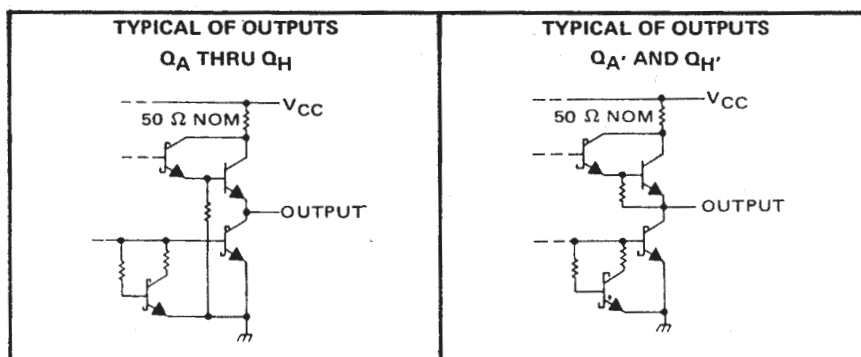
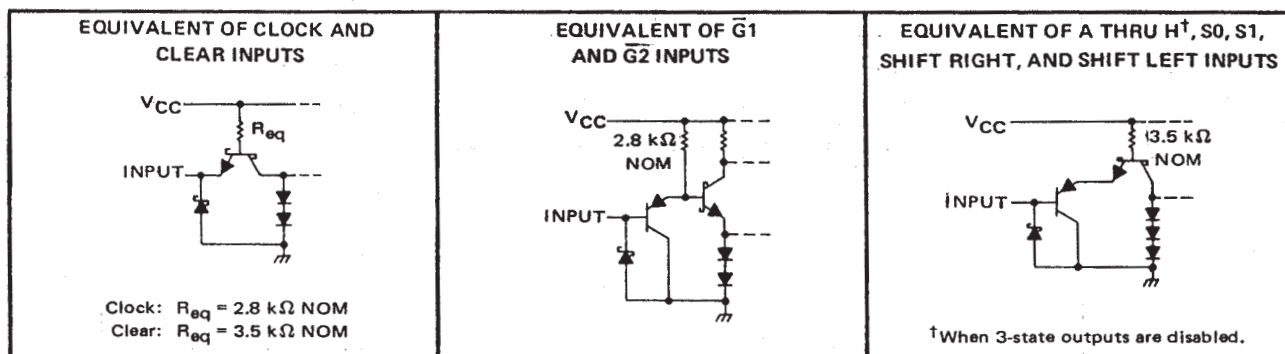
NOTE 2: For testing f_{max}, all outputs are loaded simultaneously, each with C_L and R_L as specified for the propagation times.

Load circuits and voltage waveforms are shown in Section 1.

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schematics of inputs and outputs



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} (see Note 1)	7 V
Input voltage	5.5 V
Off-state output voltage	5.5 V
Operating free-air temperature range: SN54S299 (See Note 1)	-55 °C to 125 °C
SN74S299	0 °C to 70 °C
Storage temperature range	-65 °C to 150 °C

NOTE 1: Voltage values are with respect to network ground terminal.

recommended operating conditions

	SN54S299			SN74S299			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, V_{CC}	4.5	5	5.5	4.75	5	5.25	V
High-level output current, I_{OH}	Q_A thru Q_H			-2			mA
	Q_A' or Q_H'			-0.5			
Low-level output current, I_{OL}	Q_A thru Q_H			20			mA
	Q_A' or Q_H'			6			
Clock frequency, f_{clock}	0		50	0		50	MHz
Width of clock pulse, $t_{w(clock)}$	Clock high			10			ns
	Clock low			10			
Width of clear pulse, $t_{w(clear)}$	Clear low			10			ns
Setup time, t_{SU}	Select			15 \dagger			ns
	High-level data \dagger			7 \dagger			
	Low-level data \dagger			5 \dagger			
	Clear inactive-state			10 \dagger			
Hold time, t_H	Select			5 \dagger			ns
	Data \dagger			5 \dagger			
Operating free-air temperature, T_A	-55		125	0		70	°C

\dagger Data includes the two serial inputs and the eight input/output data lines.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS†	MIN	TYP‡	MAX	UNIT
V _{IH}	High-level input voltage		2			V
V _{IL}	Low-level input voltage				0.8	V
V _{IK}	Input clamp voltage	V _{CC} = MIN, I _I = -18 mA			-1.2	V
V _{OH}	High-level output voltage	Q _A thru Q _H	V _{CC} = MIN, V _{IH} = 2 V,	2.4	3.2	V
		Q _A ' or Q _H '	V _{IL} = 0.8 V, I _{OH} = MAX	2.7	3.4	
V _{OL}	Low-level output voltage	V _{CC} = MIN, V _{IH} = 2 V, V _{IL} = 0.8 V, I _{OL} = MAX			0.5	V
I _{OZH}	Off-state output current, high-level voltage applied	Q _A thru Q _H	V _{CC} = MAX, V _{IH} = 2 V, V _O = 2.4 V		100	μA
I _{OZL}	Off-state output current, low-level voltage applied	Q _A thru Q _H	V _{CC} = MAX, V _{IH} = 2 V, V _O = 0.5 V		-250	μA
I _I	Input current at maximum input voltage	V _{CC} = MAX, V _I = 5.5 V			1	mA
I _{IH}	High-level input current	A thru H, S0, S1	V _{CC} = MAX, V _I = 2.7 V		100	μA
		Any other			50	
I _{IL}	Low-level input current	CLK or CLR	V _{CC} = MAX, V _I = 0.5 V		-2	mA
		S0, S1			-500	μA
		Any other			-250	μA
		Q _A thru Q _H			-40	-100
Q _A ' or Q _H '		-20	-100			
I _{CC}	Supply current	V _{CC} = MAX		140	225	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡ All typical values are at V_{CC} = 5 V, T_A = 25°C.

§ Not more than one output should be shorted at a time and duration of the short-circuit should not exceed one second.

switching characteristics, V_{CC} = 5 V, T_A = 25°C

PARAMETER¶	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
f _{max}			See Note 2	50	70		MHz
t _{PLH}	CLK	Q _A ' or Q _H '	R _L = 1 kΩ, C _L = 15 pF		12	20	ns
t _{PHL}					13	20	
t _{PHL}	CLR	Q _A ' or Q _H '			14	21	ns
t _{PLH}	CLK	Q _A thru Q _H	R _L = 280 Ω, C _L = 45 pF		15	21	ns
t _{PHL}					15	21	
t _{PHL}	CLR	Q _A thru Q _H			16	24	ns
t _{PZH}	G ₁ , G ₂	Q _A thru Q _H			10	18	ns
t _{PZL}					12	18	
t _{PHZ}	G ₁ , G ₂	Q _A thru Q _H	R _L = 280 Ω, C _L = 5 pF		7	12	ns
t _{PLZ}					7	12	

¶ f_{max} = maximum clock frequency

t_{PLH} = Propagation delay time, low-to-high-level output

t_{PHL} = Propagation delay time, high-to-low-level output

t_{PZH} = output enable time to high level

t_{PZL} = output enable time to low level

t_{PHZ} = output disable time from high level

t_{PLZ} = output disable time from low level

NOTE 2: For testing f_{max}, all outputs are loaded simultaneously, each with C_L and R_L as specified for the propagation times.

Load circuits and voltage waveforms are shown in Section 1.

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